



Network for Computational Nanotechnology (NCN)

Purdue, Norfolk State, Northwestern, MIT, Molecular Foundry, UC Berkeley, Univ. of Illinois, UTEP

WIND: A HTML5 Presentation Production Tool

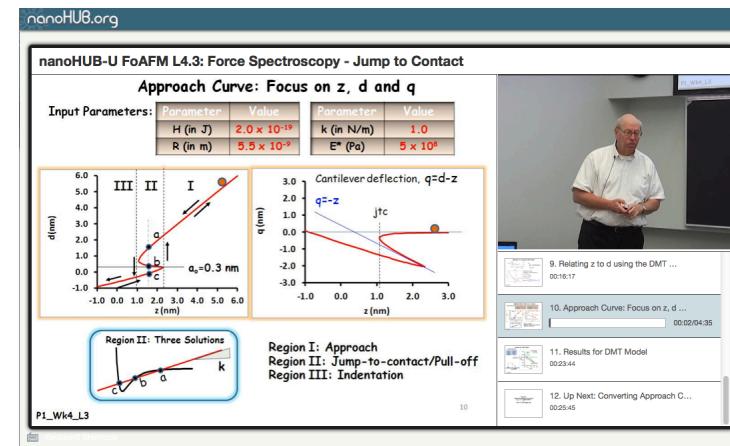
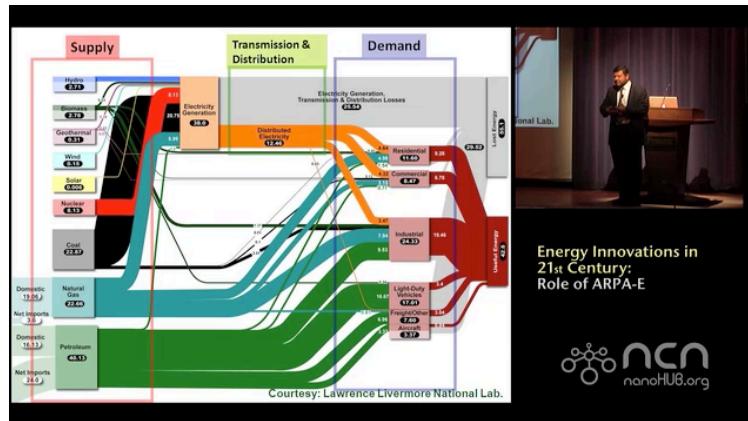
**Joseph M. Cychosz
Tianwei “David” Liu**

Network for Computational Nanotechnology (NCN)



Monday, September 24, 2012



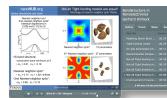


Video

MP4 640x360

MP4 854x480

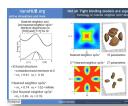




August 2002 – First online presentation: [Nanoelectronics and the Future of Microelectronics](#) - Lundstrom

April 2004 – First Breeze presentations

August 2004 – First course: [Fundamentals of Nanoelectronics](#) - Datta



March 2006 – Podcast Prototype project
[Bandstructure in Nanoelectronics](#) - Klimeck

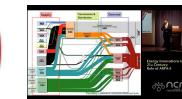
[Nanosystems Biology](#) - Heath

[Introduction to BioMEMS and Bionanotechnology](#) - Bashir



Fall 2006 – First podcast course: [Nanophotonics](#) - Shalaev

2008 – iTunes U



July 2010 – First YouTube content
 First HD podcast (640x360): [NCN Summer School](#)



Fall 2011 – Last course using Breeze, first HTML5:
[Electronic Transport in Semiconductors](#) - Lundstrom
 First HTML5 only course: [Engineering Nanomedical Systems](#) - Leary



January 2012 – First nanohub-u course:
[Fundamental of Nanoelectronics](#) - Datta

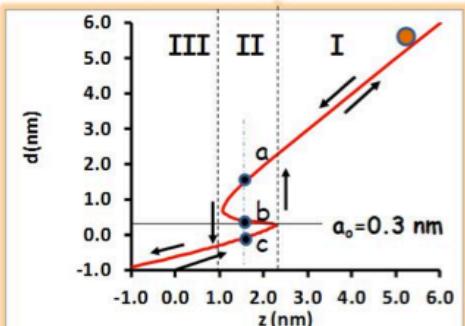


nanoHUB.org

nanoHUB-U FoAFM L4.3: Force Spectroscopy - Jump to Contact

Approach Curve: Focus on z, d and q

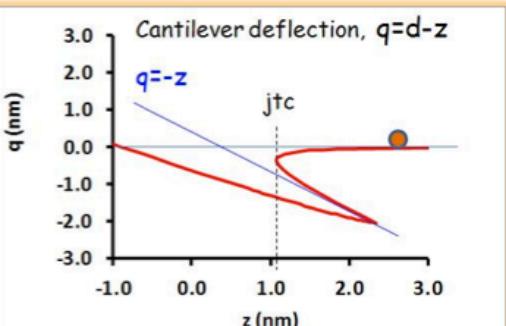
Input Parameters:	
Parameter	Value
H (in J)	2.0×10^{-19}
R (in m)	5.5×10^{-9}
k (in N/m)	1.0
E^* (Pa)	5×10^8



$d(\text{nm})$

$z(\text{nm})$

$a_0 = 0.3 \text{ nm}$



Cantilever deflection, $q=d-z$

$q=-z$

jtc

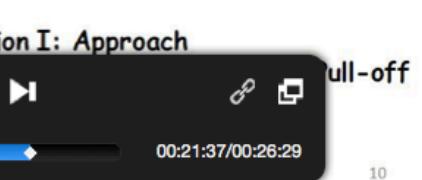
$z(\text{nm})$

Region II: Three Solutions

Region I: Approach

P1_Wk4_L3

nanohub.org/resources/14350/watch#



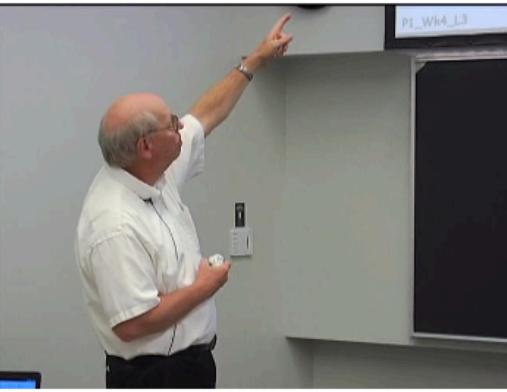
10

9. Relating z to d using the DMT ...
00:16:17

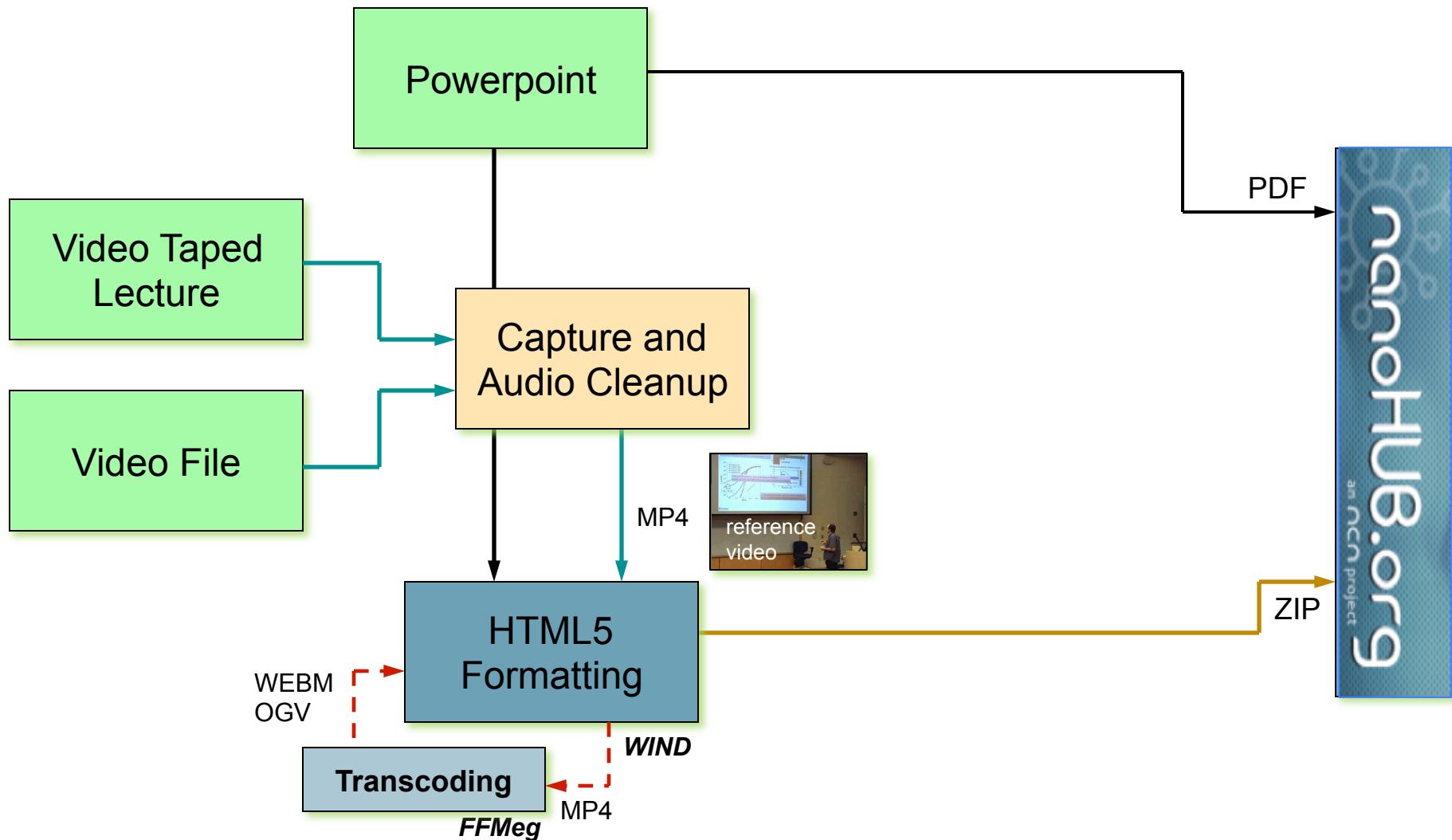
10. Approach Curve: Focus on z, d ...
00:28/04:35

11. Results for DMT Model
00:23:44

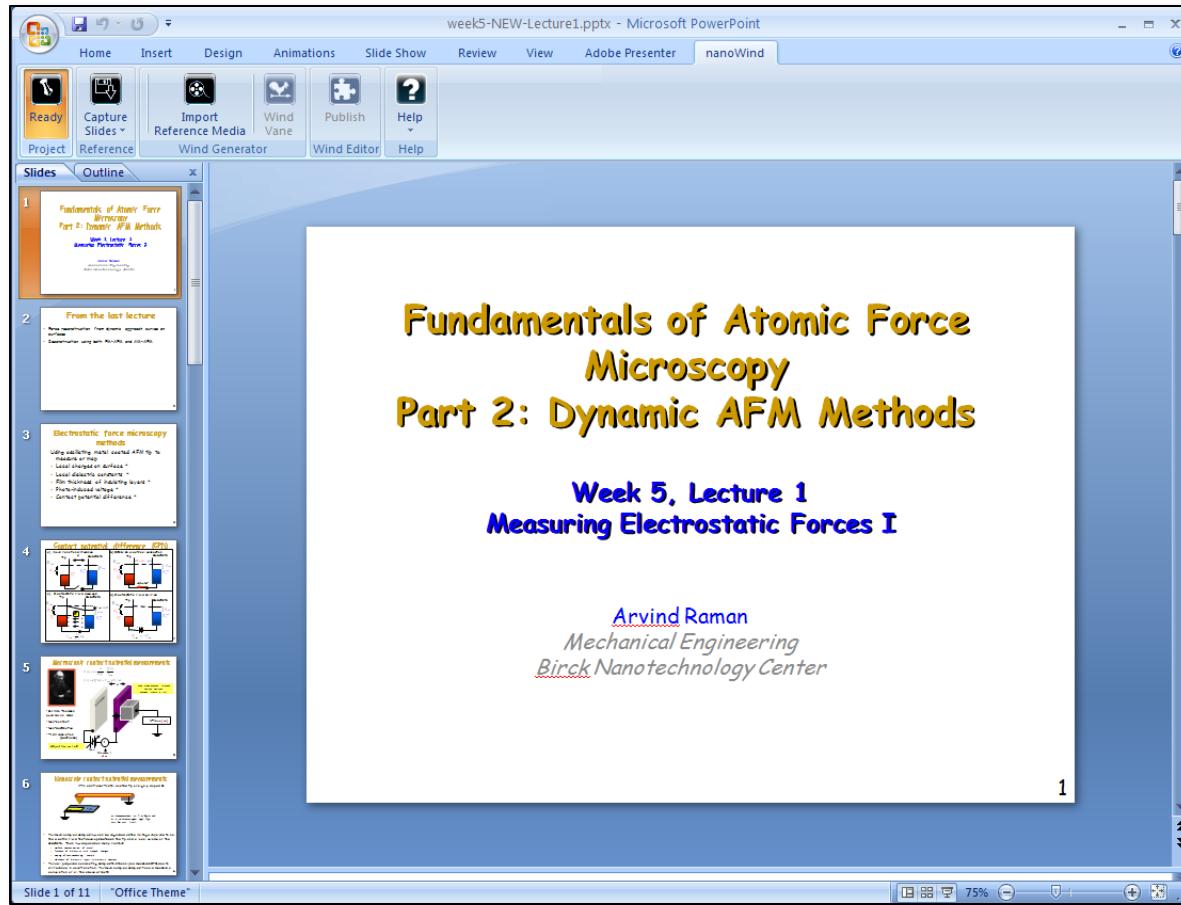
12. Up Next: Converting Approach C...
00:25:45



HUBpresenter implemented for HUBzero by Chris Smoak



- ✓ Create Project
- ✓ Capture Slides
- ✓ Reference Video
- ✓ Slide Transistions
- ✓ Table of Contents
- ✓ Publish

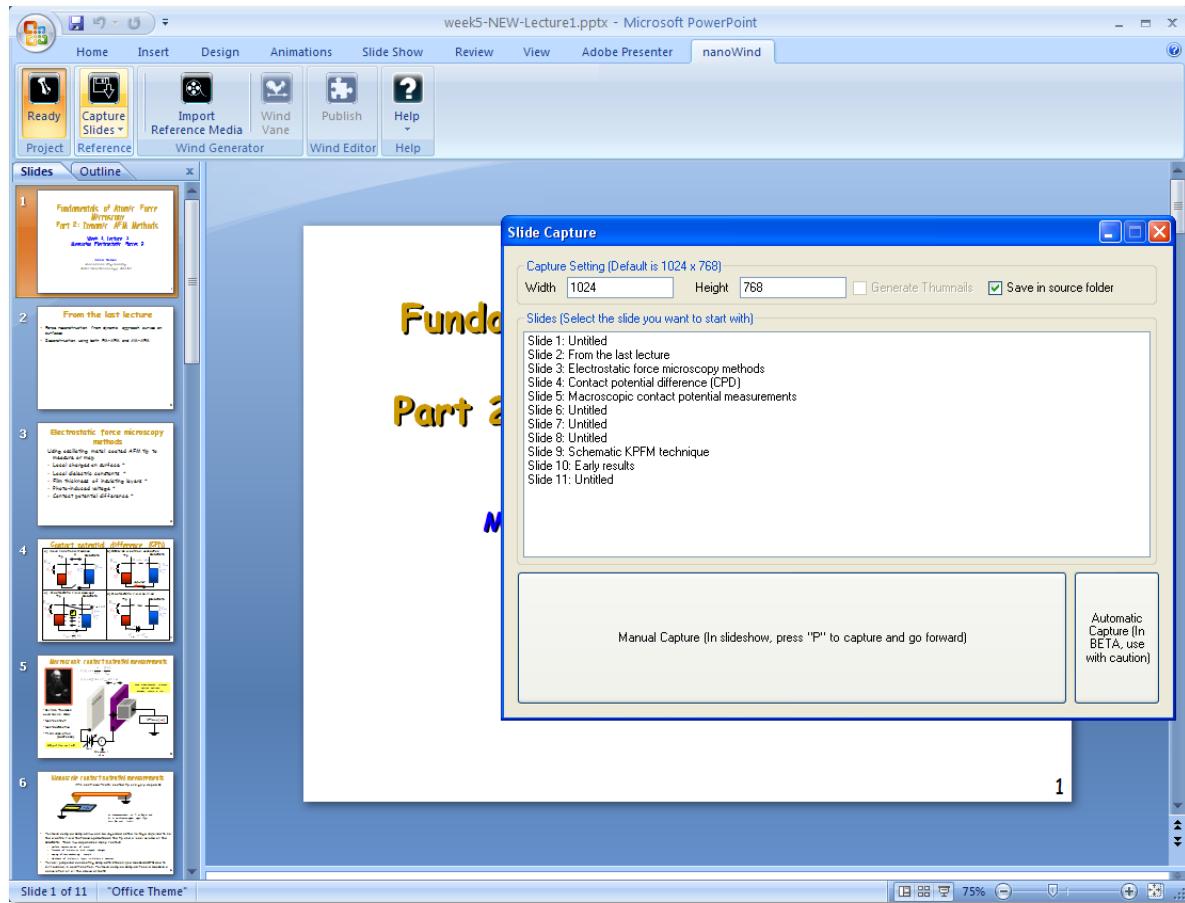


The screenshot shows a Microsoft PowerPoint slide titled "Fundamentals of Atomic Force Microscopy Part 2: Dynamic AFM Methods". The slide content includes:

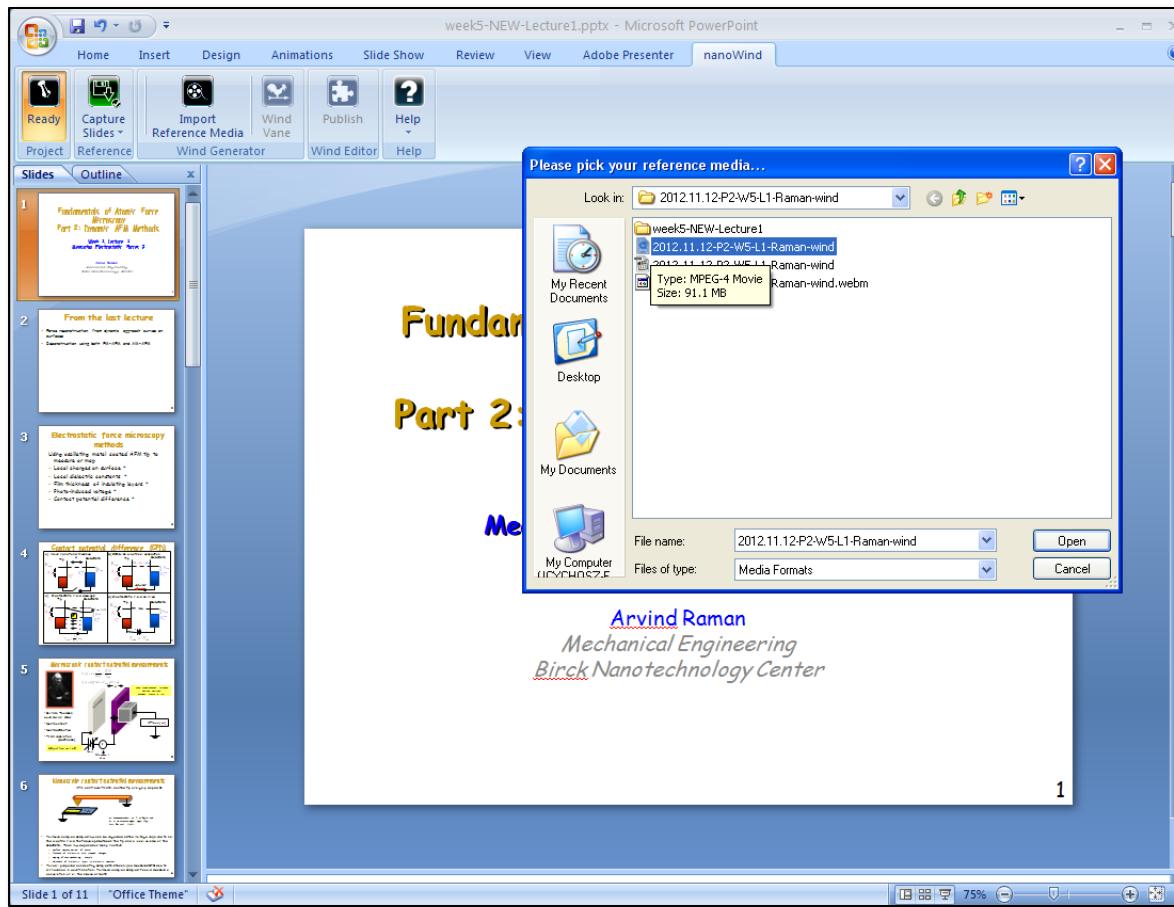
- Fundamentals of Atomic Force Microscopy**
- Part 2: Dynamic AFM Methods**
- Week 5, Lecture 1**
- Measuring Electrostatic Forces I**
- Arvind Raman**
- Mechanical Engineering**
- Birck Nanotechnology Center**

The slide number is 1. The navigation bar at the bottom indicates "Slide 1 of 11" and "Office Theme".

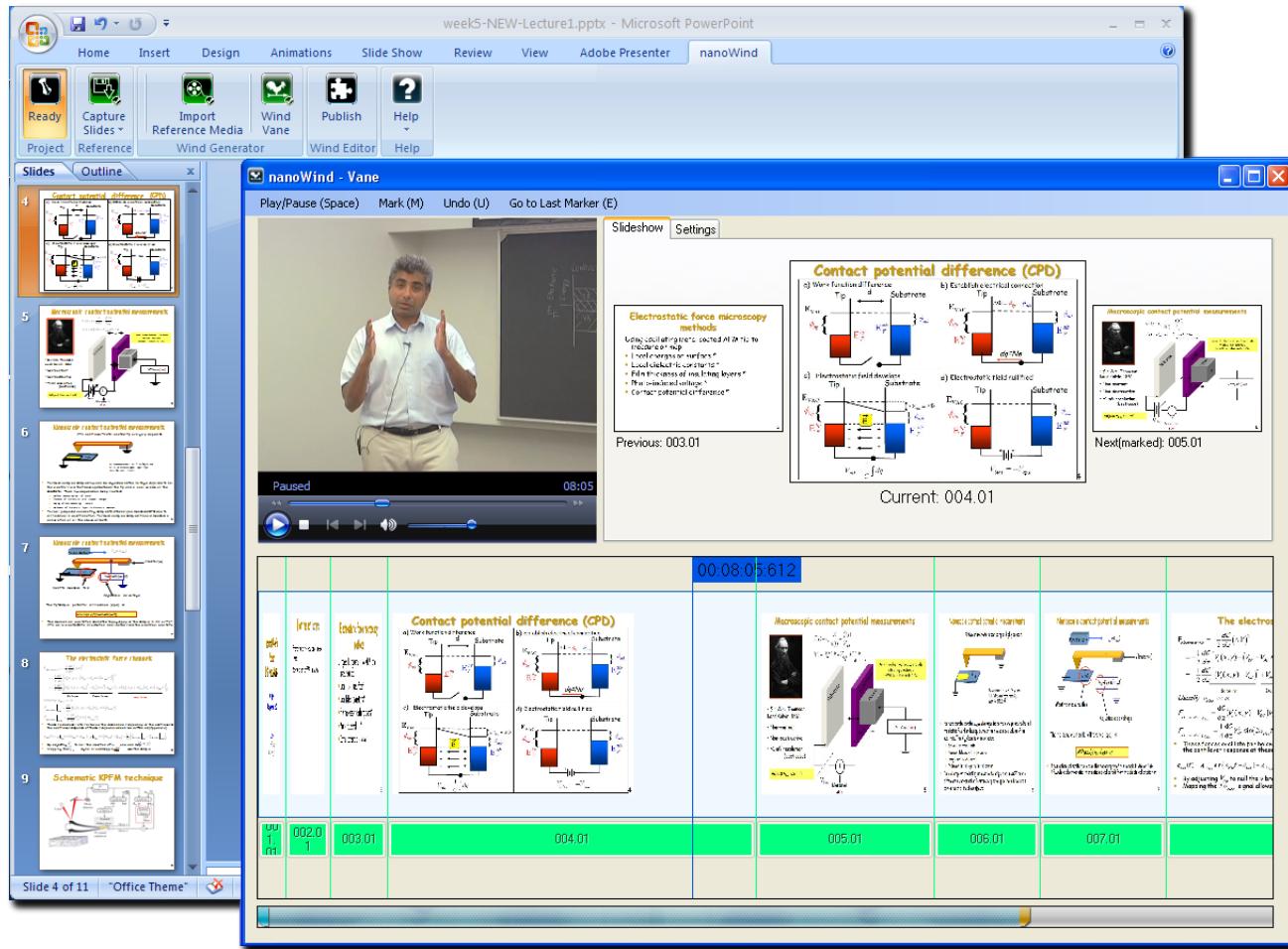
Step 2: Capture Slides



Step 3: Reference Video



Step 4: Slide Transitions



- Play/Pause (space)
- Set Mark (M)
- Undo Last Mark (U)
- Position to Last Mark (E)

week5-NEW-Lecture1.pptx - Microsoft PowerPoint

Home Insert Design Animations Slide Show Review View Adobe Presenter nanoWind

Ready Project Capture Slides Reference Media Import Wind Vane Publish Wind Generator Help Help

Slides Outline

1 Fundamentals of Atomic Force Microscopy Part 2: Nanoscale AFM Methods

2 From the last lecture

3 Electrostatic force microscopy methods

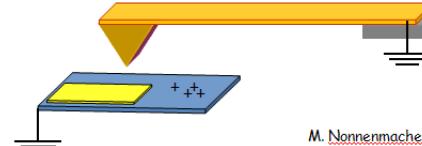
4 Contact potential difference (CPD)

5 Dielectric constant measurements

6 Mass air / electrostatic instruments

Nanoscale contact potential measurements

AFM cantilever -Metal coated tip or highly doped Si

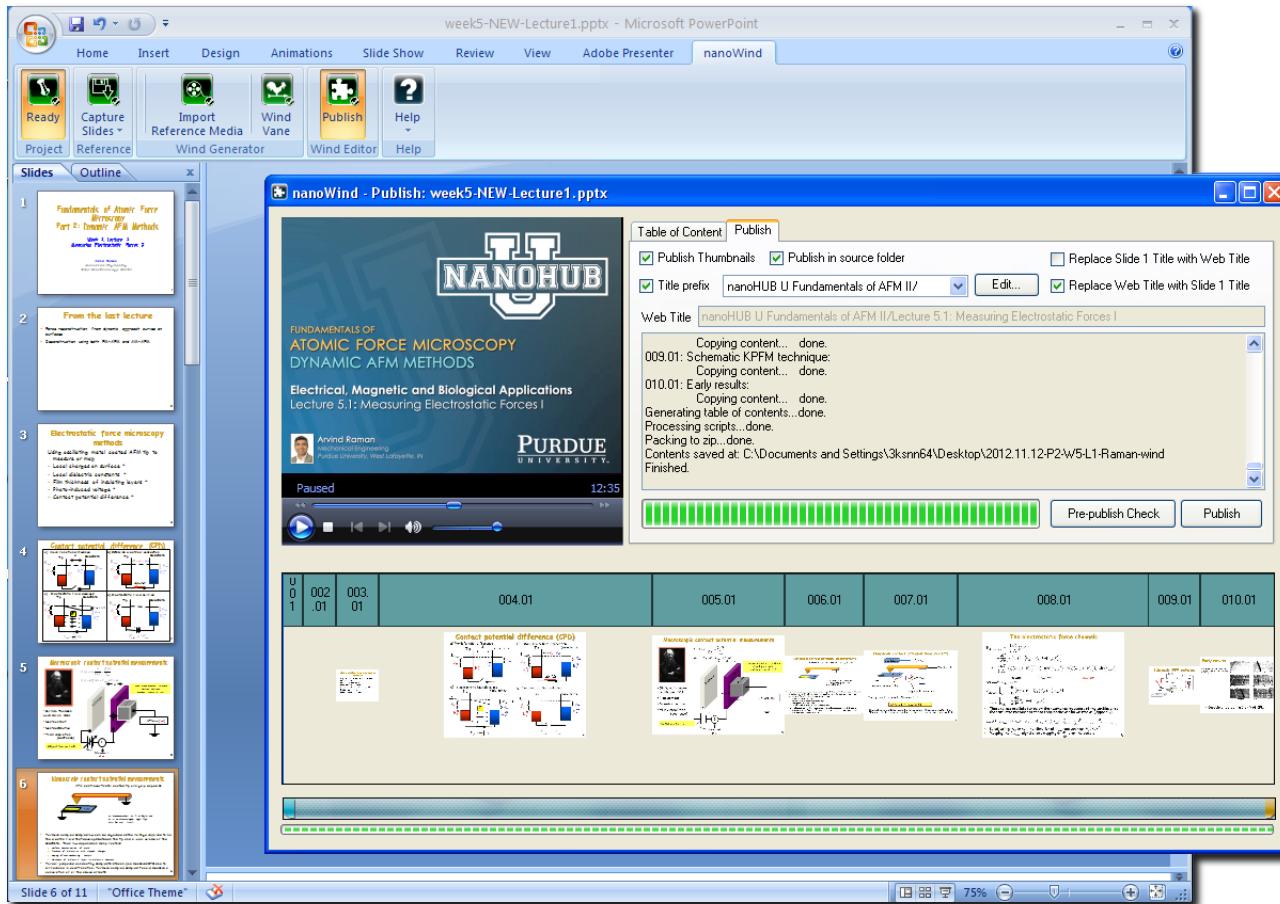


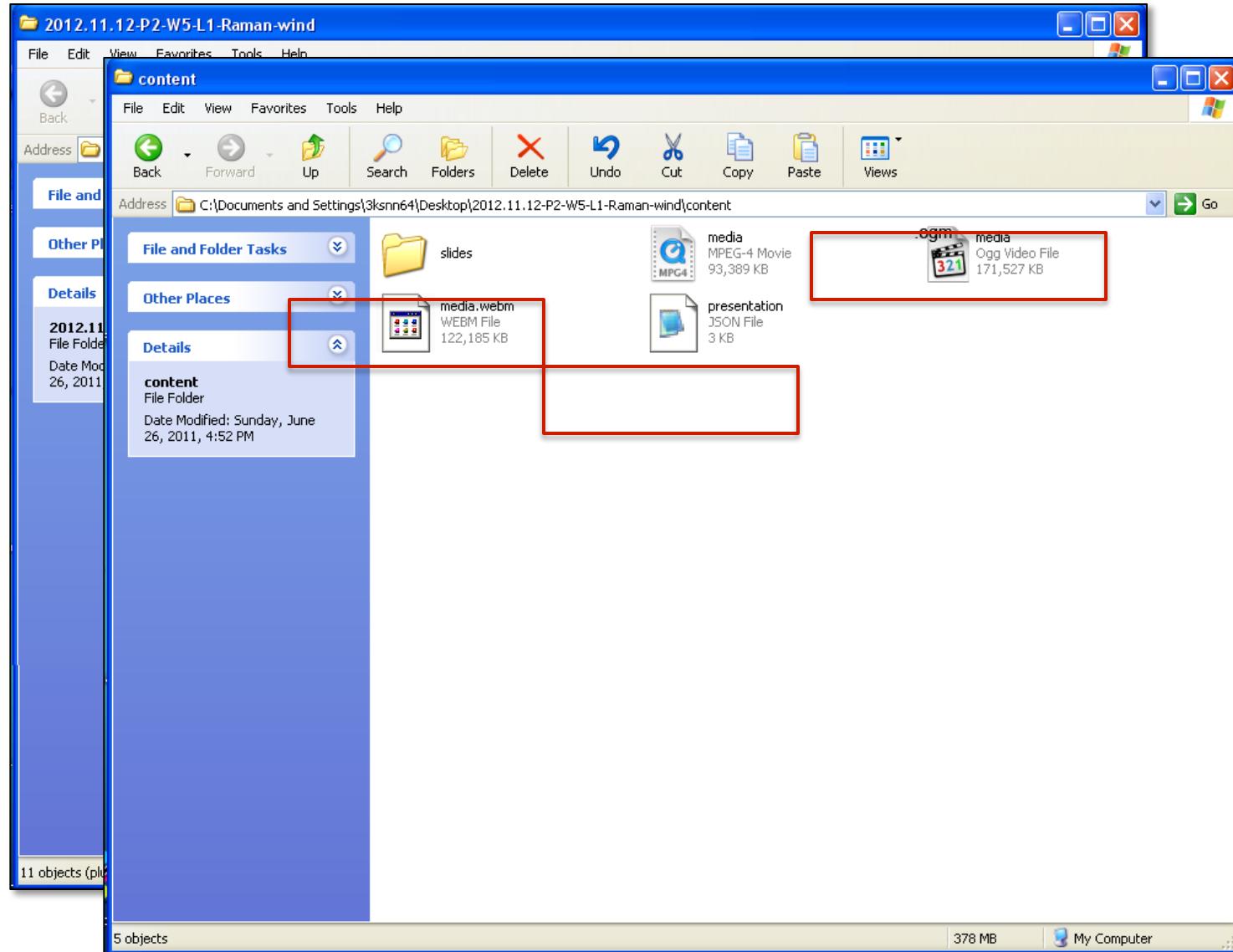
M. Nonnenmacher, M. P. O'Boyle, and H. K. Wickramasinghe, *Appl. Phys. Lett.*, 58, 2921 (1991).

- For more complex samples V_{cpd} can be regarded as the Voltage required to null the electric field that develops between the tip and a local volume of the substrate. Then V_{cpd} depends on many factors
 - Surface contamination of metal
 - Presence of dielectrics with trapped charges
 - Doping of semiconducting sample
 - Thickness of dielectric layer, its dielectric constant

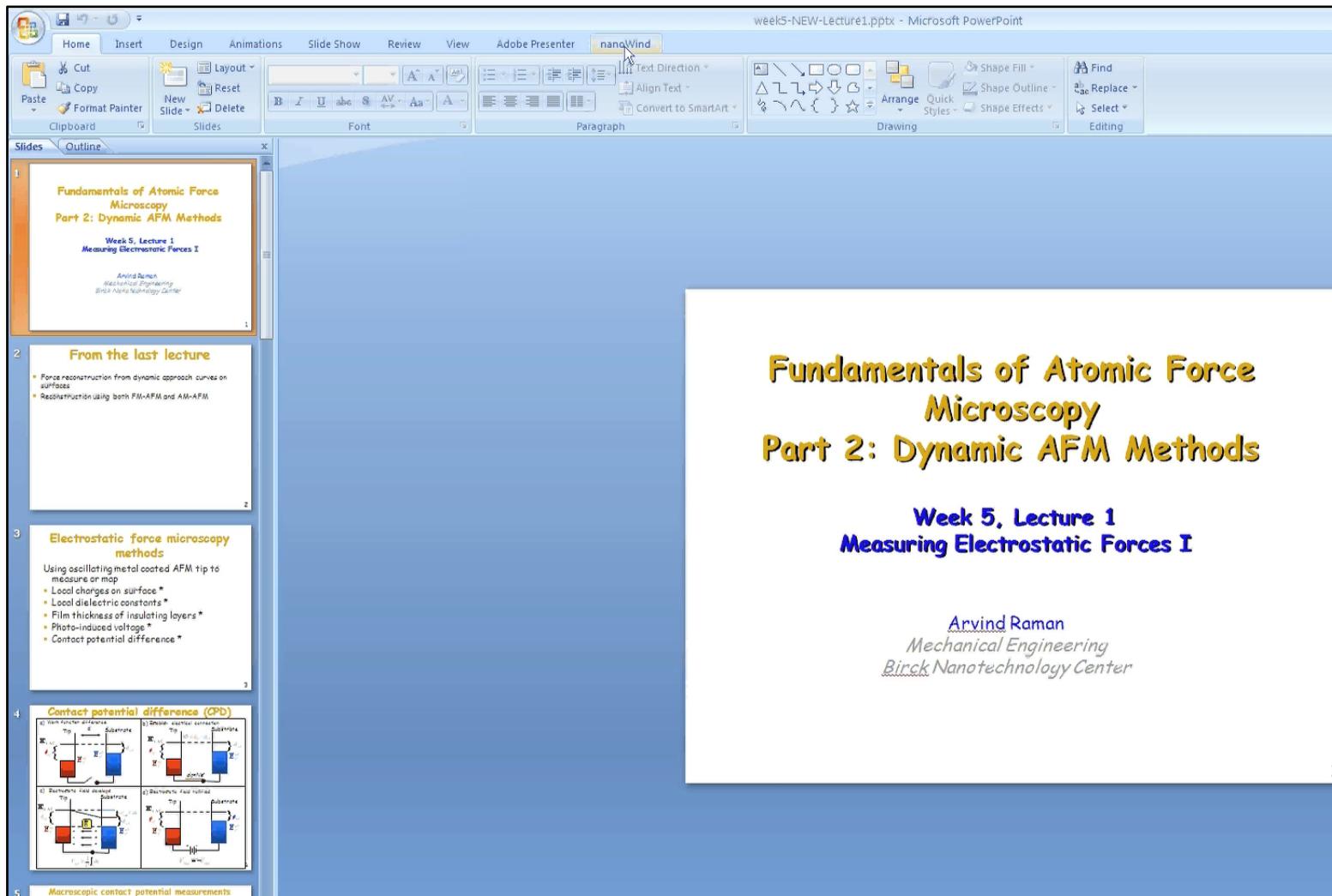
Slide 6 of 11 | "Office Theme"

Step 6: Publish





week5-NEW-Lecture1.pptx - Microsoft PowerPoint



Fundamentals of Atomic Force Microscopy
Part 2: Dynamic AFM Methods

Week 5, Lecture 1
Measuring Electrostatic Forces I

Arvind Raman
Mechanical Engineering
Birck Nanotechnology Center

From the last lecture

- Force reconstruction from dynamic approach curves on surfaces
- Reconstruction using both PFM-AFM and AM-AFM

Electrostatic force microscopy methods

Using oscillating metal coated AFM tip to measure or map

- Local charges on surface *
- Local dielectric constants *
- Film thickness of insulating layers *
- Photo-induced voltage *
- Contact potential difference *

Contact potential difference (CPD)

Macroscopic contact potential measurements

Video demo ~7:00.



- Apple Keynote now supported!!!

Keynote exports slide images including animation steps

Keynote export to Powerpoint

Powerpoint only used to hold the presentation structure



- Adobe PDF

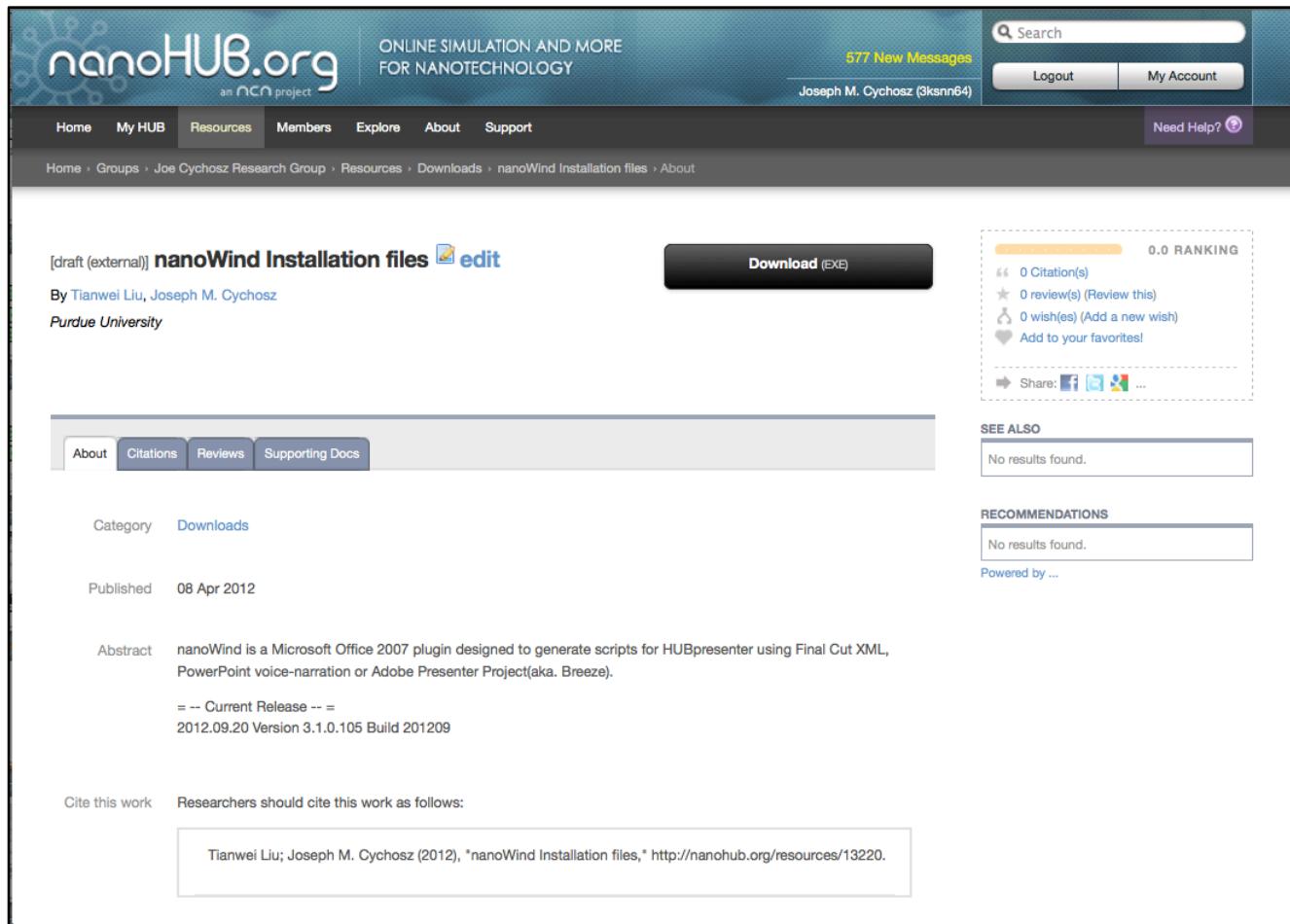
Screen capture slides

Wondershare: Free PDF to PPT Online

<http://www.free-pdfstoppt.com/>

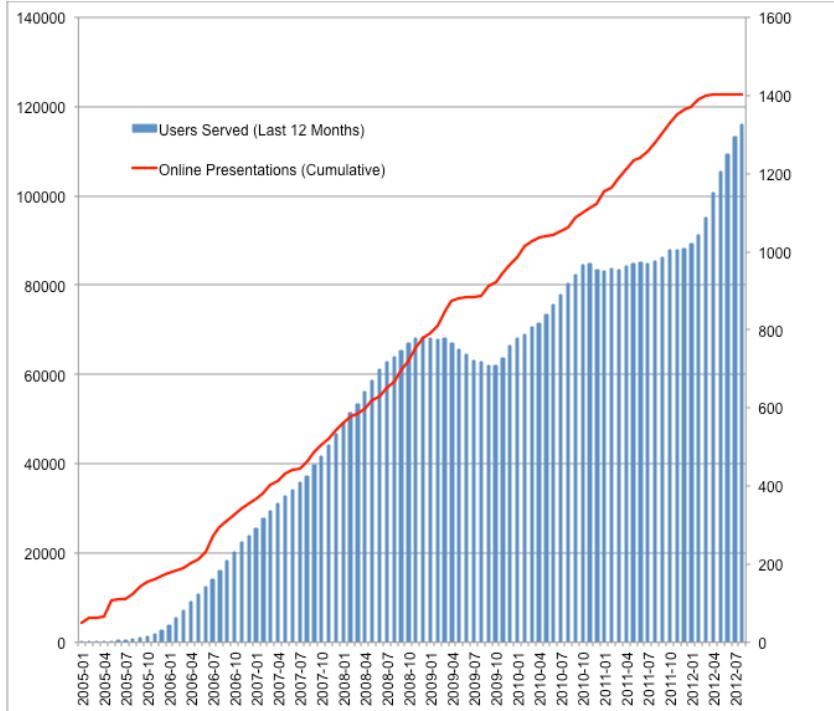
Available on nanoHUB.org at:

<http://nanohub.org/resources/13220>



The screenshot shows the nanoHUB.org website interface. At the top, there's a navigation bar with links for Home, My HUB, Resources (which is selected), Members, Explore, About, and Support. On the right side of the header, there are links for 577 New Messages, Joseph M. Cychosz (3ksnn64), Logout, My Account, and Need Help?.

The main content area displays a resource titled "[draft (external)] nanoWind Installation files" by Tianwei Liu and Joseph M. Cychosz from Purdue University. A large "Download (.EXE)" button is prominently displayed. To the right of the download button is a "RANKING" section showing 0.0 RANKING, 0 citation(s), 0 review(s), 0 wish(es), and a link to add it to favorites. Below this are sections for "SEE ALSO" (No results found) and "RECOMMENDATIONS" (No results found).
The resource details include Category: Downloads, Published: 08 Apr 2012, Abstract: nanoWind is a Microsoft Office 2007 plugin designed to generate scripts for HUBpresenter using Final Cut XML, PowerPoint voice-narration or Adobe Presenter Project(aka. Breeze). Current Release: 2012.09.20 Version 3.1.0.105 Build 201209.
Cite this work: Researchers should cite this work as follows:
Tianwei Liu; Joseph M. Cychosz (2012), "nanoWind Installation files," <http://nanohub.org/resources/13220>.



Tianwei "David" Liu, Zhipeng Laing, Carl Sommer, Joe Cychosz, Rick Desutter, Mike Hlava, (not shown) Mario Hernandez

And the HUBzero Team

A quality online learning experience requires paying attention to the details.
There are a lot of details.

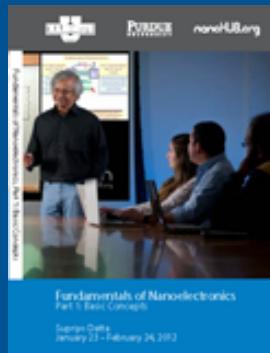
www.nanohub.org/u



5-WEEK ONLINE COURSES

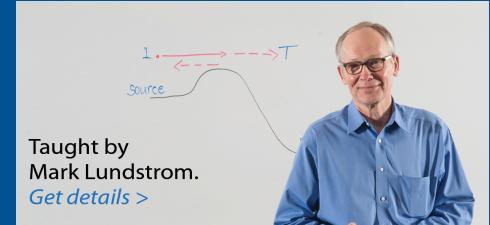


Part 2 “Dynamic AFM” Starts Soon – Registration Now Open



FUNDAMENTALS NANOELECTRONICS

Now Available for Self Paced Study – Registration Open
(Also available on DVD with free online access)



NANOSCALE TRANSISTORS

Coming This Fall – Registration Now Open

FUNDAMENTALS ATOMIC FORCE MICROSCOPY

